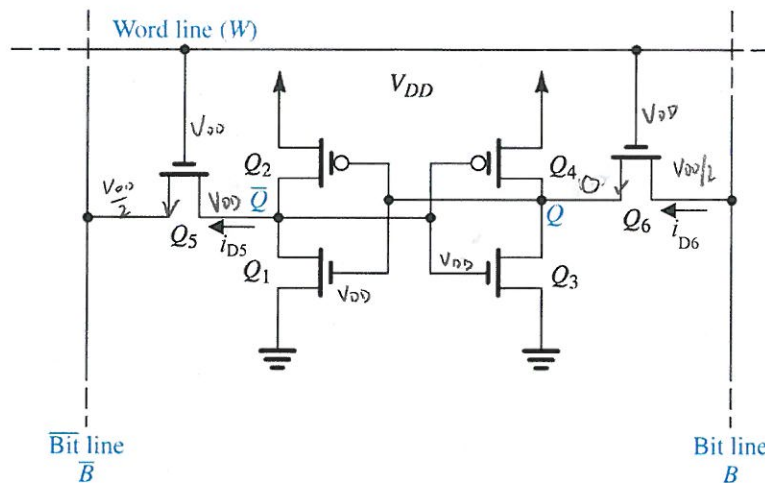


Name Solution

Section \_\_\_\_\_

1. In the figure below the voltage at  $Q$  represents the value stored in the cell and the voltage at  $\bar{Q}$  represents the complement of the stored value. Suppose that the cell stores a '0'. Consequently,  $v_Q = 0\text{ V}$  and  $v_{\bar{Q}} = V_{DD}$ . Prior to the word line being raised to  $V_{DD}$ , both  $Bit$  and  $\bar{Bit}$  are pre-charged to  $\frac{V_{DD}}{2}$ . Note that this is different from the text where they are pre-charged to  $V_{DD}$ . As is common,  $V_{tn} = -V_{tp} = 0.2 V_{DD}$ .



- a. Determine the voltages and currents for the table below **immediately** after the word line is raised to  $V_{DD}$ . Also determine the condition of the transistor (Off, On-Triode, On-Saturation) for each. If  $|v_{GS}| > |V_t|$ , but  $|v_{DS}| = 0$ , record the condition as On-No current. Remember that for NMOS transistors,  $v_S < v_D$ .

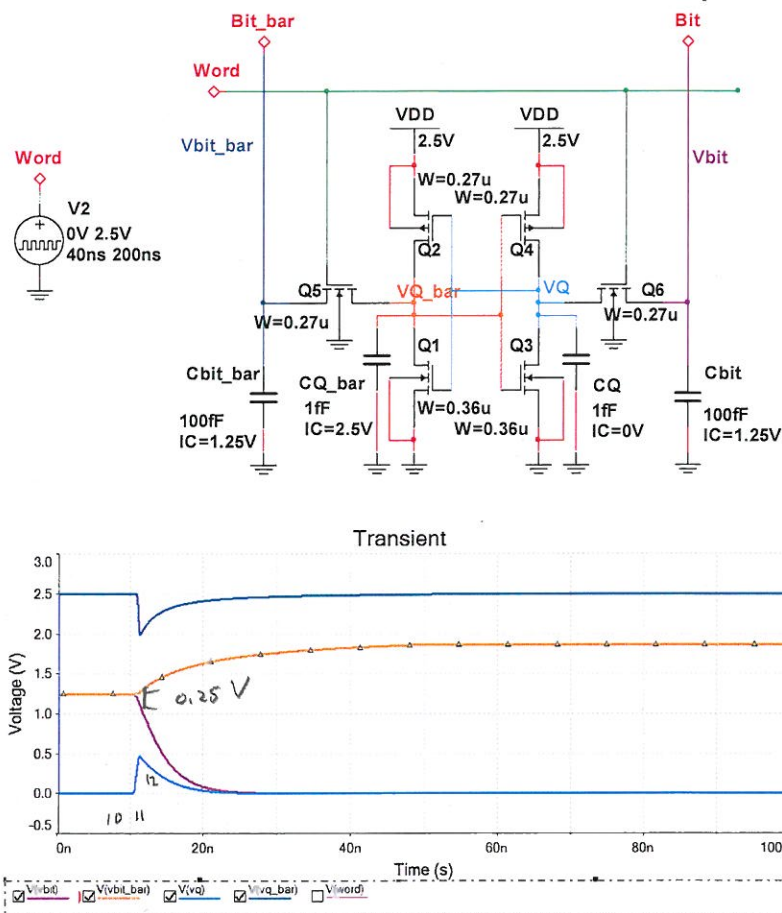
Transistor	$ v_{GS} $	$ v_{GS}  -  V_t $	$ v_{DS} $	Condition
$Q_3$	$V_{DD}$	$V_{DD} - V_t$	0	On-No current
$Q_5$	$V_{DD}/2$	$V_{DD}/2 - V_t$	$V_{DD}/2$	On-Sat
$Q_6$	$V_{DD}$	$V_{DD} - V_t$	$V_{DD}/2$	On-Triode

- b. Solve for  $i_{D5}$  and  $i_{D6}$  as a function of  $k$  for the access transistors,  $k_a = k'_n \left(\frac{W}{L}\right)_a$ , and  $V_{DD}$ . (Ignore channel-length modulation.) Simplify your answer.

$$\begin{aligned}
 i_{D5} &= \frac{1}{2} K_a \left( \frac{V_{DD}}{2} - V_t \right)^2 = \frac{1}{2} K_a (0.5V_{DD} - 0.2V_{DD})^2 = \frac{1}{2} K_a V_{DD}^2 \cdot 0.09 \\
 &= K_a V_{DD}^2 \cdot 0.045 \\
 i_{D6} &= K_a \left[ (V_{DD} - V_t) \frac{V_{DD}}{2} - \frac{1}{2} \left( \frac{V_{DD}}{2} \right)^2 \right] \\
 &= K_a [(0.8V_{DD})(0.5V_{DD}) - 0.125 V_{DD}^2] \\
 &= K_a (0.4 - 0.125) V_{DD}^2 \\
 &= K_a V_{DD}^2 \cdot 0.275
 \end{aligned}$$

On:  $|v_{GS}| > |V_t|$ ; Triode:  $|v_{DS}| \leq |v_{GS}| - |V_t|$  or  $|v_{GD}| > |V_t|$ ;  $i_D = k \left[ (|v_{GS}| - |V_t|) |v_{DS}| - \frac{1}{2} v_{DS}^2 \right]$ ;  
 Saturation:  $|v_{DS}| \geq |v_{GS}| - |V_t|$  or  $|v_{GD}| < |V_t|$ ;  $i_D = \frac{k}{2} (|v_{GS}| - |V_t|)^2 (1 + \lambda |v_{DS}|)$

2. The figures below show the same circuit in Multisim performing the read operation. Four voltages are shown in the waveform diagram. The Word line is raised to  $V_{DD}$  at  $t=10$  ns, with a 1-ns rise time. The magnitude of the threshold voltages for all transistors is  $0.2 V_{DD}$ .  $\mu_n = 2.5 \mu_p$



- Explain why  $V(vbit)$  falls faster than  $V(vbit\_bar)$  rises. (if your answers to part b are correct these equations give you the answer, but you could think it through without the equations too).  
*The drive on  $Q_4$  is much smaller so even though it is in saturation its current is smaller than that of  $Q_6 \Rightarrow V_{bit}$  falls faster current is about 6x bigger in  $Q_6$*
- Briefly explain why  $V(vbit)$  falls all the way to 0 V, while  $V(vbit\_bar)$  only rises to 1.9 V.  
*- Degraded level  $Q_4$  turns off when  $V_{bit\_bar} = V_{DD} - V_t$*
- If the sense amplifier has a differential gain of 10 V/V, estimate the time required for a read from this memory. Hint: the outputs of the sense amplifier should be at the supply rails which implies  $v_{bit} - v_{bit\_bar} = 0.25$  V

*looks like about 2ns after word starts to rise  
1ns after word reaches  $V_{DD}$*

$$\frac{(W/L)_a}{(W/L)_n} \leq \frac{1}{\left(1 - \frac{V_{tn}}{V_{DD} - V_{tn}}\right)^2} - 1 \quad \frac{(W/L)_p}{(W/L)_a} \leq \left(\frac{\mu_n}{\mu_p}\right) \left[1 - \left(1 - \frac{V_{tn}}{V_{DD} - V_{tn}}\right)^2\right]$$